



ISO7240A ISO7241A ISO7242A

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SLLS905E -MAY 2008-REVISED JANUARY 2010

# 1-Mbps QUAD DIGITAL ISOLATORS

Check for Samples: ISO7240A, ISO7241A, ISO7242A

#### **FEATURES**

- 4000-V<sub>peak</sub> Isolation, 560-V<sub>peak</sub> V<sub>IORM</sub>
  - UL 1577, IEC 60747-5-2 (VDE 0884, Rev 2),
     IEC 61010-1, IEC 60950-1 and CSA
     Approved
- 4 kV ESD Protection
- Operate With 3.3-V or 5-V Supplies
- Typical 25-Year Life at Rated Working Voltage (See Application Note (SLLA197) and Figure 10)
- High Electromagnetic Immunity (See Application Report (SLLA181))
- –40°C to 125°C Operating Range

#### **APPLICATIONS**

- Industrial Fieldbus
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

#### **DESCRIPTION**

See the Product Notification section. The ISO7240A, ISO7241A and ISO7242A are quad-channel digital isolators with multiple channel configurations and output enable functions. These devices have logic input and output buffers separated by Ti's silicon dioxide (SiO<sub>2</sub>) isolation barrier. Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents from entering the local ground and interfering with or damaging sensitive circuitry.

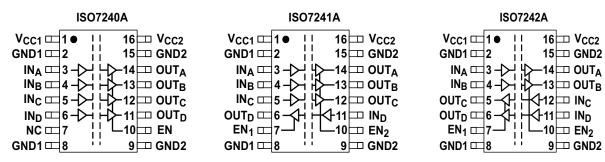
The ISO7240A has all four channels in the same direction while the ISO7241A has three channels the same direction and one channel in opposition. The ISO7242A has two channels in each direction.

The devices have TTL input thresholds and a noise-filter at the input that prevents transient pulses from being passed to the output of the device.

A periodic update pulse is sent across the barrier to ensure the proper dc level of the output. If this dc-refresh pulse is not received, the input is assumed to be unpowered or not being actively driven, and the failsafe circuit drives the output to a logic high state. (See ISO7240CF (SLLS869) or contact TI for a logic low failsafe option).

These devices may be powered from either 3.3-V or 5-V supplies on either side in any 3.3-V / 3.3-V, 5-V / 5-V, 5-V / 3.3-V, or 3.3-V / 5-V combination. Note that the signal input pins are 5-V tolerant regardless of the voltage supply level being used.

These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### **FUNCTION DIAGRAM**

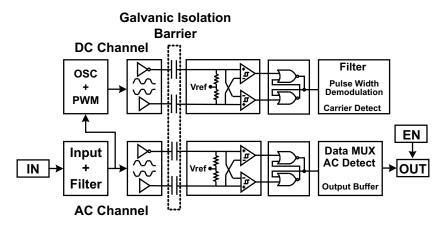


Table 1. Device Function Table ISO724x (1)

INPUT V <sub>CC</sub>	OUTPUT V <sub>CC</sub>	INPUT (IN)	OUTPUT ENABLE (EN)	OUTPUT (OUT)
		Н	H or Open	Н
DU	PU	L	H or Open	L
PU		Х	L	Z
		Open	H or Open	Н
PD	PU	Х	H or Open	Н
PD	PU	Х	L	Z

(1) PU = Powered Up; PD = Powered Down; X = Irrelevant; H = High Level; L = Low Level

#### **AVAILABLE OPTIONS**

PRODUCT	SIGNALING RATE	INPUT THRESHOLD	CHANNEL CONFIGURATION	MARKED AS	ORDERING NUMBER <sup>(1)</sup>
ISO7240ADW	1 Mbps	~1.5 V (TTL)	4/0	ISO7240A	ISO7240ADW (rail)
1307240ADW	1 Mbps	(CMOS compatible)	4/0	13072408	ISO7240ADWR (reel)
ISO7241ADW	1 Mbpo	~1.5 V (TTL)	3/1	ISO7241A	ISO7241ADW (rail)
1507241ADW	1 Mbps	(CMOS compatible)	3/1	1507241A	ISO7241ADWR (reel)
10070404 DW	4 1 1 1 1 1 1 1	~1.5 V (TTL)	0/0	10070404	ISO7242ADW (rail)
ISO7242ADW	1 Mbps	(CMOS compatible)	2/2	ISO7242A	ISO7242ADWR (reel)

For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI
website at www.ti.com.



### ABSOLUTE MAXIMUM RATINGS(1)

**NSTRUMENTS** 

					VALUE	UNIT	
$V_{CC}$	Supply voltag	e <sup>(2)</sup> , V <sub>CC1</sub> , V <sub>CC2</sub>			-0.5 to 6	V	
$V_{I}$	Voltage at IN	, OUT, EN			-0.5 to 6	V	
IO	Output current					mA	
		Human Body Model	JEDEC Standard 22, Test Method A114-C.01		±4		
ESD	Electrostatic discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1	kV	
		Machine Model	ANSI/ESDS5.2-1996		±200	V	
$T_{J}$	Maximum jun	ction temperature			170	°C	

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
$V_{CC}$	Supply voltage <sup>(1)</sup> , V <sub>CC1</sub> , V <sub>CC2</sub>		3.15		5.5	V
I <sub>OH</sub>	High-level output current				4	mA
I <sub>OL</sub>	Low-level output current		-4			mA
t <sub>ui</sub>	Input pulse width	ISO724xA	1			μS
1/t <sub>ui</sub>	Signaling rate	ISO724xA	0		1000	kbps
$V_{IH}$	High-level input voltage (IN) (EN on all devices)	es)	2		V <sub>CC</sub>	V
$V_{IL}$	Low-level input voltage (IN) (EN on all devices)	ISO724xA	0		0.8	V
TJ	Junction temperature				150	°C
Н	External magnetic field-strength immunity per IEC certification	C 61000-4-8 and IEC 61000-4-9			1000	A/m

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.

#### IEC 60747-5-2 INSULATION CHARACTERISTICS(1)

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	SPECIFICATIONS	UNIT
$V_{IORM}$	Maximum working insulation voltage		560	V
		After Input/Output Safety Test Subgroup 2/3 $V_{PR} = V_{IORM} \times 1.2$ , t = 10 s, Partial discharge < 5 pC	672	V
$V_{PR}$	Input to output test voltage	Method a, V <sub>PR</sub> = V <sub>IORM</sub> × 1.6, Type and sample test with t = 10 s, Partial discharge < 5 pC	896	V
		Method b1, V <sub>PR</sub> = V <sub>IORM</sub> × 1.875, 100 % Production test with t = 1 s, Partial discharge < 5 pC	1050	V
$V_{IOTM}$	Transient overvoltage	t = 60 s	4000	V
R <sub>S</sub>	Insulation resistance	$V_{IO}$ = 500 V at $T_{S}$	>10 <sup>9</sup>	Ω
· · · · · · · · · · · · · · · · · · ·	Pollution degree		2	

(1) Climatic Classification 40/125/21

<sup>(2)</sup> All voltage values are with respect to network ground terminal and are peak voltage values.



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# ELECTRICAL CHARACTERISTICS: $V_{\text{CC1}}$ and $V_{\text{CC2}}$ at 5-V $^{(1)}$ OPERATION

, over recommended operating conditions (unless otherwise noted)

	PAR	AMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT			•		*	
	10070404	Quiescent	V V sa OV All shaded and Lord EN at OV		1	3	0
	ISO7240A	1 Mbps	$V_1 = V_{CC}$ or 0 V, All channels, no load, EN <sub>2</sub> at 3 V		1	3	mA
	10070444	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no load, EN <sub>1</sub> at 3 V,		0.5	4.4	A
I <sub>CC1</sub>	ISO7241A	1 Mbps	EN <sub>2</sub> at 3 V		6.5	11	mA
	10070404	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no load, EN <sub>1</sub> at 3 V,		10	16	A
	ISO7242A	1 Mbps	EN <sub>2</sub> at 3 V		10	16	mA
	10070404	Quiescent	V V OV All shores less less I EN ( OV		15	22	0
	ISO7240A	1 Mbps	$V_1 = V_{CC}$ or 0 V, All channels, no load, EN <sub>2</sub> at 3 V		16	22	mA
	10070444	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no load, EN <sub>1</sub> at 3 V,		13	20	A
-	ISO7241A	1 Mbps	EN <sub>2</sub> at 3 V		13	20	mA
	10070404	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no load, EN <sub>1</sub> at 3 V,		10	16	0
	ISO7242A	1 Mbps	EN <sub>2</sub> at 3 V		10	16	mA
ELECTI	RICAL CHAR	ACTERISTICS					
I <sub>OFF</sub>	Sleep mode	e output current	EN at 0 V, Single channel		0		μА
V	∐iah laval a	output voltage	I <sub>OH</sub> = -4 mA, See Figure 1	$V_{CC} - 0.8$		V	
V <sub>OH</sub>	nigii-level c	output voltage	$I_{OH} = -20 \mu A$ , See Figure 1	V <sub>CC</sub> - 0.1			V
V	l our lovel o	utout voltogo	I <sub>OL</sub> = 4 mA, See Figure 1			0.4	V
V <sub>OL</sub>	Low-level o	utput voltage	$I_{OL}$ = 20 $\mu$ A, See Figure 1			0.1	V
$V_{I(HYS)}$	Input voltag	e hysteresis			150		mV
I <sub>IH</sub>	High-level in	nput current	IN from 0 \/ to \/			10	^
I <sub>IL</sub>	Low-level input current		IN from 0 V to V <sub>CC</sub>	-10			μΑ
Cı	Input capac	citance to ground	IN at $V_{CC}$ , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-m	node transient immunity	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 4	25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.

#### SWITCHING CHARACTERISTICS: V<sub>CC1</sub> and V<sub>CC2</sub> at 5-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	Con Figure 4	40 95			
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	See Figure 1	1			ns
t <sub>sk(o)</sub>	Channel-to-channel output skew (2)				2	ns
t <sub>r</sub>	Output signal rise time	Con Figure 4	2			
t <sub>f</sub>	Output signal fall time	See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impedance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-high-level output	Con Figure 0		15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impedance output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-low-level output			15	20	
t <sub>fs</sub>	Failsafe output delay time from input power loss	See Figure 3		12		μS

<sup>(1)</sup> Also referred to as pulse skew.

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 <sup>(2)</sup> t<sub>sk(o)</sub> is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



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# ELECTRICAL CHARACTERISTICS: V<sub>CC1</sub> at 5-V, V<sub>CC2</sub> at 3.3-V<sup>(1)</sup> OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAME	TER	TEST CONI	DITIONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT				•		•	
	10070404	Quiescent	\/ \/ \- \- \- \\ \ \ \ \ \ \ \ \ \ \ \	and the stand		1	3	0
	ISO7240A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels	, no load, EN <sub>2</sub> at 3 V		1	3	mA
	10070444	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels	, no load, EN <sub>1</sub> at 3 V,		0.5	4.4	A
I <sub>CC1</sub>	ISO7241A	1 Mbps	EN <sub>2</sub> at 3 V			6.5	11	mA
	10070404	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load, EN <sub>1</sub> at 3 V,		10	16	A	
	ISO7242A	1 Mbps	EN <sub>2</sub> at 3 V			10	16	mA
	10072404	Quiescent	\/ \/ or 0 \/ All channels	no load TN at 2 V		9.5	15	A
	ISO7240A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels	, no load, Ein <sub>2</sub> at 3 V		10	15	mA
	ISO7241A	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels	$V_1 = V_{CC} \ \text{or} \ 0 \ \text{V}, \ \text{All channels, no load, EN}_1 \ \text{at} \ 3 \ \text{V}, \ \text{EN}_2 \ \text{at} \ 3 \ \text{V}$		8	13	A
I <sub>CC2</sub>	1507241A	1 Mbps	1			8	13	mA
	10070404	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels	, no load, EN <sub>1</sub> at 3 V,		6	10	A
	ISO7242A	1 Mbps	EN <sub>2</sub> at 3 V			6	10	mA
ELECTI	RICAL CHARAC	TERISTICS			·			
l <sub>OFF</sub>	Sleep mode ou	utput current	EN at 0 V, Single channel			0		μΑ
			L - 4 mA Soo Figure 1	ISO7240A	$V_{CC} - 0.4$			
$V_{OH}$	High-level outp	out voltage	I <sub>OH</sub> = -4 mA, See Figure 1	ISO724x (5-V side)	V <sub>CC</sub> - 0.8			V
			$I_{OH} = -20 \mu A$ , See Figure 1		V <sub>CC</sub> - 0.1			
V	Low-level outp	ut voltogo	I <sub>OL</sub> = 4 mA, See Figure 1				0.4	V
$V_{OL}$	Low-level outp	ut voltage	$I_{OL}$ = 20 $\mu$ A, See Figure 1				0.1	V
$V_{I(HYS)}$	Input voltage h	ysteresis				150		mV
I <sub>IH</sub>	High-level inpu	it current	INI from O \/ to \/				10	^
I <sub>IL</sub>	Low-level inpu	t current	IIN IIOIII O A 10 ACC	from 0 V to V <sub>CC</sub>				μΑ
Cı	Input capacitar	nce to ground	IN at $V_{CC}$ , $V_{I} = 0.4 \sin (4E6\pi t)$	t)		2		pF
CMTI	Common-mode	e transient immunity	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 4	1	25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.

# SWITCHING CHARACTERISTICS: V<sub>CC1</sub> at 5-V, V<sub>CC2</sub> at 3.3-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	See Figure 4	40		100	
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	See Figure 1			11	ns
	Channel to about all output all out (2)				3	
t <sub>sk(o)</sub>	Channel-to-channel output skew (2)			0	1	ns
t <sub>r</sub>	Output signal rise time	Con Figure 4		2		
t <sub>f</sub>	Output signal fall time	See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impedance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-high-level output	Can Figure 2		15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impedance output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-low-level output			15	20	
t <sub>fs</sub>	Failsafe output delay time from input power loss	See Figure 3		18		μS

Also known as pulse skew

<sup>(2)</sup>  $t_{sk(o)}$  is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



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# ELECTRICAL CHARACTERISTICS: V<sub>CC1</sub> at 3.3-V, V<sub>CC2</sub> at 5-V<sup>(1)</sup> OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMET	ER	TEST CON	DITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT						,	
	10070404	Quiescent	V V an O.V. All alcandala	Land EN 110 V		0.5	1	A
	ISO7240A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no	load, EIN <sub>2</sub> at 3 V		1	2	mA
	10070111	Quiescent	., ., ., ., ., .			4	4 7	
I <sub>CC1</sub>	ISO7241A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no	Tillels, 110 loau, Elv1 at 3 v, Elv2 at 3 v		4	7	mA
	10070404	Quiescent	V <sub>I</sub> = V <sub>CC</sub> or 0 V, All channels, no load, EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		6	10		
	ISO7242A	1 Mbps	$V_{I} = V_{CC}$ or 0 V, All channels, no	load, EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		6	10	mA
		Quiescent				15	22	
	ISO7240A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no	load, EN <sub>2</sub> at 3 V		16	22	mA
		Quiescent				13	6 1 1 2 4 7 6 10 6 10 6 22 6 22 8 20 16 0 16 0 16 0 10 10 10 10 10 10 10 10 10 10 10 10 1	
I <sub>CC2</sub>	ISO7241A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no	load, EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V			mA	
		Quiescent				10	16	
	ISO7242A	1 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no	load, EN <sub>1</sub> at 3 V, EN <sub>2</sub> at 3 V		10		mA
ELECTR	ICAL CHARA	CTERISTICS						
I <sub>OFF</sub>	Sleep mode	output current	EN at V <sub>CC</sub> , Single channel			0		μΑ
		-		ISO7240A	V <sub>CC</sub> - 0.4			
$V_{OH}$	High-level of	output voltage	I <sub>OH</sub> = -4 mA, See Figure 1	ISO724x (5-V side)	V <sub>CC</sub> - 0.8			V
			$I_{OH} = -20 \mu A$ , See Figure 1		V <sub>CC</sub> - 0.1		1 2 7 7 10 10 22 22 20 20 16 16	
			I <sub>OL</sub> = 4 mA, See Figure 1				0.4	
$V_{OL}$	Low-level o	utput voltage	I <sub>OL</sub> = 20 μA, See Figure 1				0.1	V
V <sub>I(HYS)</sub>	Input voltag	e hysteresis				150		mV
I <sub>IH</sub>	High-level in	nput current					10	
I <sub>IL</sub>	Low-level in	put current	IN from 0 V to V <sub>CC</sub>	from 0 V to V <sub>CC</sub>				μΑ
C <sub>I</sub>	Input capac ground	itance to	IN at $V_{CC}$ , $V_I = 0.4 \sin (4E6\pi t)$			2		pF
CMTI	Common-m	ode transient	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 4		25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.

#### SWITCHING CHARACTERISTICS: $V_{CC1}$ at 3.3-V and $V_{CC2}$ at 5-V OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	Con Figure 4	40		100	
PWD	Pulse-width distortion <sup>(1)</sup>  t <sub>PHL</sub> - t <sub>PLH</sub>	See Figure 1			11	ns
	Observation also and automatical and (2)				2.5	
t <sub>sk(o)</sub>	Channel-to-channel output skew (2)			0	1	ns
t <sub>r</sub>	Output signal rise time	0		2		
t <sub>f</sub>	Output signal fall time	See Figure 1		2		ns
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impedance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-high-level output	0 Firms 0		15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impedance output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-low-level output			15	20	
t <sub>fs</sub>	Failsafe output delay time from input power loss	See Figure 3		12		μS

<sup>(1)</sup> Also known as pulse skew

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<sup>(2)</sup> t<sub>sk(o)</sub> is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



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# ELECTRICAL CHARACTERISTICS: $V_{CC1}$ and $V_{CC2}$ at 3.3 $V^{(1)}$ OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAME	TER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT			•		•	
	10070404	Quiescent	V V and V all abounds and local EN at 0 V		0.5	1	1
	ISO7240A	1 Mbps	$V_I = V_{CC}$ or 0 V, all channels, no load, EN <sub>2</sub> at 3 V		1	2	mA
	10070444	Quiescent	$V_1 = V_{CC}$ or 0 V, all channels, no load, EN <sub>1</sub> at 3 V,		4	7	
I <sub>CC1</sub>	ISO7241A	1 Mbps	EN <sub>2</sub> at 3 V		4	7	A
	ISO7242A	Quiescent	$V_1 = V_{CC}$ or 0 V, all channels, no load, EN <sub>1</sub> at 3 V,		6	10	mA
	1507242A	1 Mbps	EN <sub>2</sub> at 3 V		6	10	
•	ISO7240A	Quiescent	V V or 0 V all channels no load EN at 2 V		9.5	15	mA
	1507240A	1 Mbps	$V_I = V_{CC}$ or 0 V, all channels, no load, $EN_2$ at 3 V		10	15	mA
	ISO7241A	Quiescent	$V_1 = V_{CC}$ or 0 V, all channels, no load, EN <sub>1</sub> at 3 V,		8	13	
	1307241A	1 Mbps	EN <sub>2</sub> at 3 V		8	13	mA
	ISO7242A	Quiescent	$V_I = V_{CC}$ or 0 V, all channels, no load, EN <sub>1</sub> at 3 V,		6	10	IIIA
	1307242A	1 Mbps	EN <sub>2</sub> at 3 V		6	10	
ELECTI	RICAL CHARACT	ERISTICS					
I <sub>OFF</sub>	Sleep mode out	put current	EN at 0 V, single channel		0		μΑ
V	High-level outpu	ıt voltago	I <sub>OH</sub> = -4 mA, See Figure 1	V <sub>CC</sub> - 0.4			V
V <sub>OH</sub>	r light-level outpu	it voltage	$I_{OH} = -20 \mu A$ , See Figure 1	$V_{CC} - 0.1$			V
V	Low-level outpu	t voltogo	I <sub>OL</sub> = 4 mA, See Figure 1			0.4	V
V <sub>OL</sub>	Low-level outpu	i voltage	I <sub>OL</sub> = 20 μA, See Figure 1			0.1	V
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I <sub>IH</sub>	High-level input	current	IN from 0 \/ or \/			10	
I <sub>IL</sub>	Low-level input	current	IN from 0 V or V <sub>CC</sub>	-10			μА
Cı	Input capacitano	ce to ground	IN at V <sub>CC</sub> , V <sub>I</sub> = 0.4 sin (4E6πt)		2		pF
CMTI	Common-mode	transient immunity	V <sub>I</sub> = V <sub>CC</sub> or 0 V, See Figure 4	25	50		kV/μs

<sup>(1)</sup> For the 5-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 4.5 V to 5.5 V. For the 3-V operation,  $V_{CC1}$  or  $V_{CC2}$  is specified from 3.15 V to 3.6 V.

#### SWITCHING CHARACTERISTICS: V<sub>CC1</sub> and V<sub>CC2</sub> at 3.3-V OPERATION

over recommended operating conditions (unless otherwise noted)

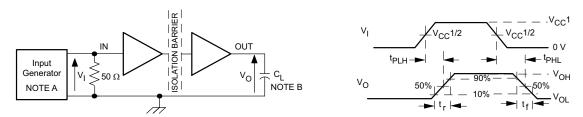
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub> , t <sub>PHL</sub>	Propagation delay	See Figure 4	45		110	
PWD	Pulse-width distortion  t <sub>PHL</sub> - t <sub>PLH</sub>   <sup>(1)</sup>	See Figure 1			12	ns
	Channel to showed output alread (2)				3.5	
t <sub>sk(o)</sub>	Channel-to-channel output skew (2)			0	1	
t <sub>r</sub>	Output signal rise time	0		2		ns
t <sub>f</sub>	Output signal fall time	See Figure 1		2		
t <sub>PHZ</sub>	Propagation delay, high-level-to-high-impedance output			15	20	
t <sub>PZH</sub>	Propagation delay, high-impedance-to-high-level output	See Figure 2		15	20	
t <sub>PLZ</sub>	Propagation delay, low-level-to-high-impedance output	See Figure 2		15	20	ns
t <sub>PZL</sub>	Propagation delay, high-impedance-to-low-level output			15	20	
t <sub>fs</sub>	Failsafe output delay time from input power loss	See Figure 3		18		μS

<sup>1)</sup> Also referred to as pulse skew.

<sup>(2)</sup> t<sub>sk(o)</sub> is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

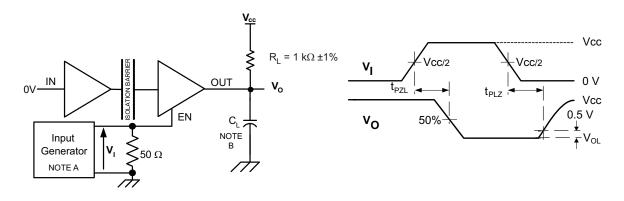


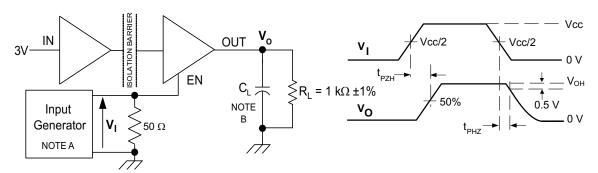
#### PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \leq$  3 ns,  $Z_O = 50\Omega$ .
- B.  $C_L = 15$  pF and includes instrumentation and fixture capacitance within  $\pm 20\%$ .

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms



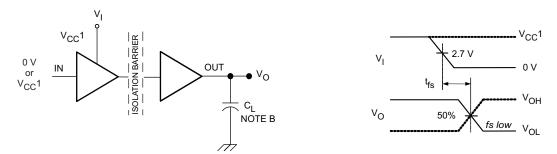


- A. The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \leq$  3 ns,  $Z_O = 50\Omega$ .
- B.  $C_L = 15$  pF and includes instrumentation and fixture capacitance within  $\pm 20\%$ .

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform

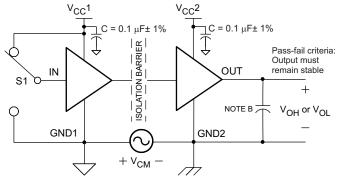
**INSTRUMENTS** 

#### PARAMETER MEASUREMENT INFORMATION (continued)



- $C_L$  = 15 pF and includes instrumentation and fixture capacitance within ±20%.
- The input pulse is supplied by a generator having the following characteristics: PRR ≤ 50 kHz, 50% duty cycle, t<sub>r</sub> ≤ 3 ns,  $t_f \le 3$  ns,  $Z_O = 50\Omega$ .

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



- $C_L$  = 15 pF and includes instrumentation and fixture capacitance within ±20%.
- The input pulse is supplied by a generator having the following characteristics: PRR  $\leq$  50 kHz, 50% duty cycle,  $t_r \leq$  3 ns,  $t_f \le 3$  ns,  $Z_O = 50\Omega$ .

Figure 4. Common-Mode Transient Immunity Test Circuit and Voltage Waveform



#### **DEVICE INFORMATION**

## **PACKAGE CHARACTERISTICS**

	PARAMETER	PARAMETER TEST CONDITIONS				
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	8.34			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	8.1			mm
C <sub>TI</sub>	Tracking resistance (comparative tracking index)	DIN IEC 60112/VDE 0303 Part 1	≥ 175			V
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R <sub>IO</sub>	Isolation resistance	Input to output, $V_{IO}$ = 500 V, all pins on each side of the barrier tied together creating a two-terminal device		>10 <sup>12</sup>		Ω
C <sub>IO</sub>	Barrier capacitance Input to output	$V_1 = 0.4 \sin (4E6\pi t)$		2		pF
Cı	Input capacitance to ground	$V_1 = 0.4 \sin (4E6\pi t)$		2		pF

#### **IEC 60664-1 RATINGS TABLE**

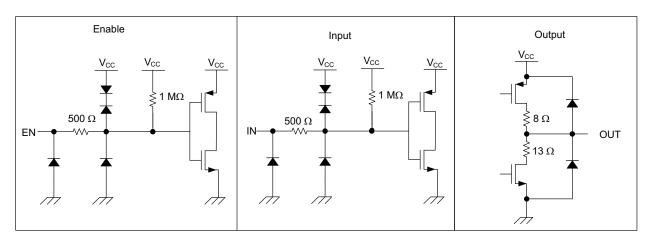
PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	Material group	IIIa
Installation classification	Rated mains voltage ≤150 VRMS	I-IV
Installation classification	Rated mains voltage ≤300 VRMS	1-111

#### **REGULATORY INFORMATION**

VDE	CSA	UL
Certified according to IEC 60747-5-2	Approved under CSA Component Acceptance Notice	Recognized under 1577 Component Recognition Program (1)
File Number: 40016131	File Number: 1698195	File Number: E181974

(1) Production tested ≥ 3000 Vrms for 1 second in accordance with UL 1577.

#### **DEVICE I/O SCHEMATICS**



# THERMAL CHARACTERISTICS

**INSTRUMENTS** 

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN 7	YP N	MAX	UNIT
	Junction-to-air	Low-K Thermal Resistance <sup>(1)</sup>		168		°C/W
$\theta_{JA}$	Junction-to-all	High-K Thermal Resistance	9	6.1		C/VV
$\theta_{JB}$	Junction-to-Board Thermal Resistance			61		°C/W
$\theta_{\text{JC}}$	Junction-to-Case Thermal Resistance			48		°C/W
$P_D$	Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.5 \text{ V}, T_J = 150^{\circ}\text{C}, C_L = 15 \text{ pF},$ Input a 50% duty cycle square wave			220	mW

<sup>(1)</sup> Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

#### TYPICAL CHARACTERISTIC CURVES

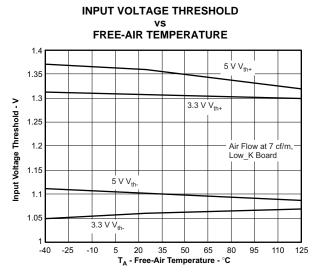
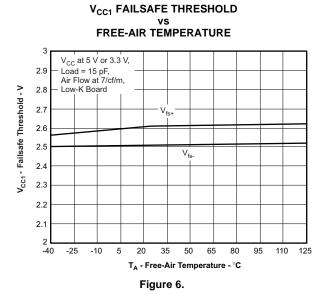


Figure 5.

HIGH-LEVEL OUTPUT CURRENT



LOW-LEVEL OUTPUT CURRENT

# HIGH-LEVEL OUTPUT VOLTAGE Told and a substitution of the substitu

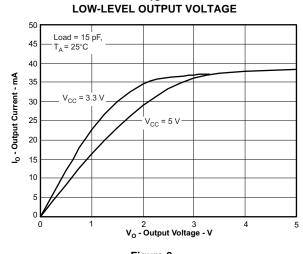


Figure 8.



#### **APPLICATION INFORMATION**

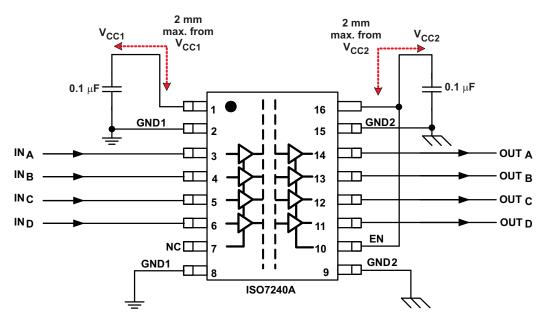


Figure 9. Typical ISO7240A Application Circuit

#### LIFE EXPECTANCY vs. WORKING VOLTAGE

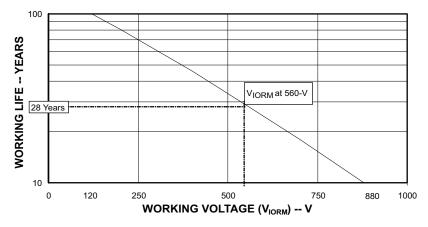


Figure 10. Time-Dependant Dielectric Breakdown Testing Results

#### PRODUCT NOTIFICATION

**INSTRUMENTS** 

An ISO724xA anomaly occurs when a negative-going pulse below the specified 1  $\mu$ s minimum bit width is input to the device. The output locks in a logic-low condition until the next rising edge occurs after a 1  $\mu$ s period.

Positive noise edges in pulses of less than the minimum specified 1  $\mu$ s have no effect on the device, and are properly filtered.

To prevent noise from interfering with ISO724xA performance, it is recommended that an appropriately sized capacitor be placed on each input of the device

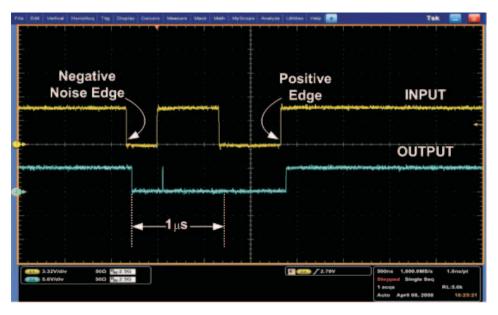


Figure 11. ISO724xA Anomaly

#### **REVISION HISTORY**

CI	hanges from Original (May 2008) to Revision A	Page
•	Changed In the PACKAGE CHARACTERISTICS table, line 1, change L <sub>(IO1)</sub> MIN value from 7.7mm to	8.34mm 10
CI	hanges from Revision A (July 2008) to Revision B	Page
•	Added information to the 1st Feature bullet to include CSA and IEC 60950-1 certification	1
•	Changed Figure 9 From: 20mm max.from V <sub>CCx</sub> To: 2mm max. from V <sub>CCx</sub> .	12
CI	hanges from Revision B (December 2008) to Revision C	Page
•	Changed I <sub>CC1</sub> for Quiescent and 1Mbps From: 10mA To: 11mA	4
	Changed I <sub>CC1</sub> for Quiescent and 1Mbps From: 10mA To: 11mA	
_		5
CI	hanges from Revision C (March 2009) to Revision D	5

# Not Recommended for New Designs

ISO7240A ISO7241A ISO7242A



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Cł	nanges from Revision D (December 2009) to Revision E	Page
•	Added the IEC 60747-5-2 INSULATION CHARACTERISTIC table	3
•	Added C <sub>TI</sub> - Tracking resistance (comparative tracking index to the PACKAGE CHARACTERISTICS table	10
•	Added the IEC 60664-1 RATINGS TABLE	10





30-Aug-2014

#### PACKAGING INFORMATION

(	Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
	ISO7240ADW	NRND	SOIC	DW	16	40	TBD	Call TI	(3) Call TI	-40 to 125	ISO7240A	
	ISO7240ADWG4	NRND	SOIC	DW	16	40	TBD	Call TI	Call TI	-40 to 125	ISO7240A	
	ISO7240ADWR	NRND	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7240A	
Į:	SO7240ADWRG4	NRND	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7240A	
	ISO7241ADW	NRND	SOIC	DW	16	40	TBD	Call TI	Call TI	-40 to 125	ISO7241A	
	ISO7241ADWG4	NRND	SOIC	DW	16	40	TBD	Call TI	Call TI	-40 to 125	ISO7241A	
	ISO7241ADWR	NRND	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7241A	
Į:	SO7241ADWRG4	NRND	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7241A	
	ISO7242ADW	NRND	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7242A	
	ISO7242ADWG4	NRND	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7242A	
	ISO7242ADWR	NRND	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7242A	
Į:	SO7242ADWRG4	NRND	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7242A	

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.



### PACKAGE OPTION ADDENDUM

30-Aug-2014

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF ISO7241A:

■ Enhanced Product: ISO7241A-EP

NOTE: Qualified Version Definitions:

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

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#### TAPE AND REEL INFORMATION





Α0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7240ADWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7241ADWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7242ADWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO7240ADWR	SOIC	DW	16	2000	367.0	367.0	38.0
ISO7241ADWR	SOIC	DW	16	2000	367.0	367.0	38.0
ISO7242ADWR	SOIC	DW	16	2000	367.0	367.0	38.0

DW (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



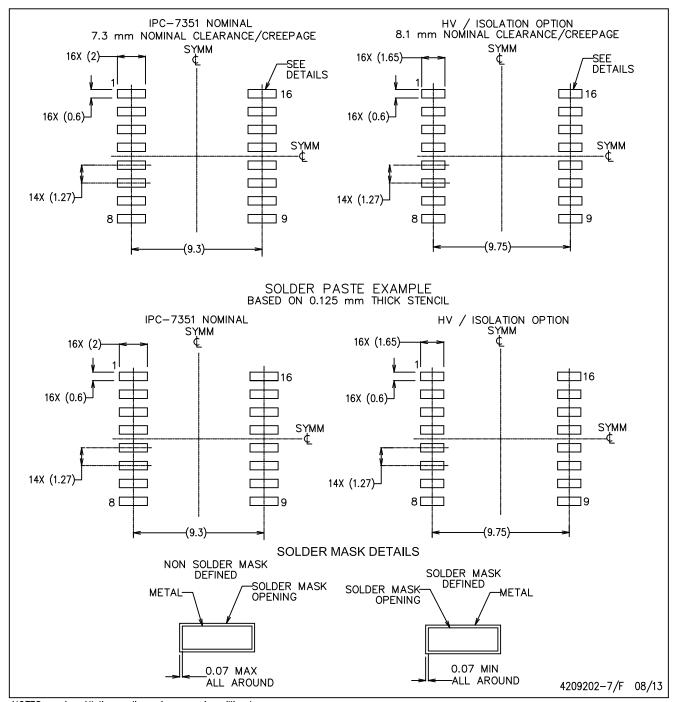
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AA.



# DW (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- E. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- F. Board assembly site may have different recommendations for stencil design.



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